

Search Notes

Application/Control No.

10/526,074

Examiner

Hau V. Phan

Applicant(s)/Patent under
Reexamination

FUKUMOTO ET AL.

Art Unit

3618

SEARCHED

Class	Subclass	Date	Examiner
180	65.2 65.1 65.4 65.3	2/1/2007	HP
	65.8		
310	219	2/1/2007	HP
	227		
	248		
60	597	2/1/2007	HP
	297		
	649		
903	903	2/1/2007	HP
	906		
	907		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Text Search	2/1/2007	HP